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SNOSAQ7A - DECEMBER 2010-REVISED MARCH 2013

# LF412JAN Low Offset, Low Drift Dual JFET Input Operational Amplifier

Check for Samples: LF412JAN

#### **FEATURES**

Input Offset Voltage Drift: 30 μV/°C (Max)
 Low Input Bias Current: 50 pA (Typ)
 Wide Gain Bandwidth: 3 MHz (Typ)

High Slew Rate: 7V/μs (Min)
 High Input Impedance: 10<sup>12</sup>Ω

Low Total Harmonic Distortion <0.02%</li>

Low 1/f Noise Corner: 50 Hz
Fast Settling Time to 0.01%: 2 µs

Low Input Noise Current: 0.01 Pa/√Hz (Typ)

#### **Connection Diagram**

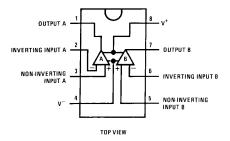


Figure 1. Dual-In-Line Package See Package Number NAB0008A

#### **DESCRIPTION**

This device is a low cost, high speed, JFET input operational amplifier with very low input offset voltage and ensured input offset voltage drift. It requires low supply current yet maintains a large gain bandwidth product and fast slew rate. In addition, well matched high voltage JFET input devices provide very low input bias and offset currents. The LF412 dual is pin compatible with the LM1558, allowing designers to immediately upgrade the overall performance of existing designs.

This amplifier may be used in applications such as high speed integrators, fast D/A converters, sample and hold circuits and many other circuits requiring low input offset voltage and drift, low input bias current, high input impedance, high slew rate and wide bandwidth.

#### Simplified Schematic

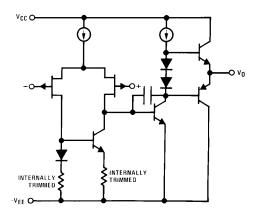


Figure 2. 1/2 Dual

A

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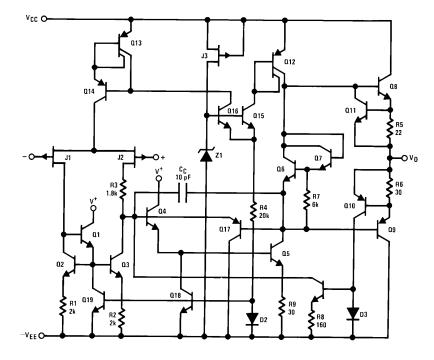
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# **Detailed Schematic**







These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

### Absolute Maximum Ratings(1)

iiga					
Supply Voltage					
Differential Input Voltage					
e Range <sup>(2)</sup>					
		Continuous			
CDIP Packa	age	800mW			
T <sub>Jmax</sub>					
0	CDIP Package (Still Air)	122°C/W			
$\Theta_{\mathrm{JA}}$	CDIP Package (500 LF/Min Air Flow)	66°C/W			
$\theta_{JC}$	CDIP Package	15°C/W			
·		±5V to ±15V			
Operating Temperature Range					
Storage Temperature Range					
Lead Temperature Soldering (10 Sec)					
		1,700V			
	CDIP Packa  θ <sub>JA</sub> θ <sub>JC</sub>	CDIP Package  θ <sub>JA</sub> CDIP Package (Still Air)  CDIP Package (500 LF/Min Air Flow)  θ <sub>JC</sub> CDIP Package			

- (1) Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not ensure specific performance limits. For ensured specifications and test conditions, see the Electrical Characteristics. The ensured specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.
- Unless otherwise specified the absolute maximum negative input voltage is equal to the negative power supply voltage.
- Any of the amplifier outputs can be shorted to ground indefinitely, however, more than one should not be simultaneously shorted as the maximum junction temperature will be exceeded.
- The maximum power dissipation must be derated at elevated temperatures and is dictated by T<sub>Jmax</sub> (maximum junction temperature),  $\theta_{JA}$  (package junction to ambient thermal resistance), and  $T_A$  (ambient temperature). The maximum allowable power dissipation at any temperature is  $P_{Dmax} = (T_{Jmax} - T_A)/\theta_{JA}$  or the number given in the Absolute Maximum Ratings, whichever is lower. Human body model, 1.5 k $\Omega$  in series with 100 pF.



# **Quality Conformance Inspection**

NSTRUMENTS

#### Table 1. Mil-Std-883, Method 5005 - Group A

Subgroup	Description	Temp (°C)
1	Static tests at	+25
2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25
5	Dynamic tests at	+125
6	Dynamic tests at	-55
7	Functional tests at	+25
8A	Functional tests at	+125
8B	Functional tests at	-55
9	Switching tests at	+25
10	Switching tests at	+125
11	Switching tests at	-55
12	Settling time at	+25
13	Settling time at	+125
14	Settling time at	-55

Product Folder Links: LF412JAN



# **Electrical Characteristics DC Parameters**

The following conditions apply, unless otherwise specified.  $\pm V_{CC} = \pm 15V$ ,  $V_{CM} = 0V$ 

Symbol	Parameter	Conditions	Notes	Min	Max	Unit	Sub- group
		+V <sub>CC</sub> = 26V, -V <sub>CC</sub> = -4V,		-5.0	5.0	mV	1
		V <sub>CM</sub> = -11V		-7.0	7.0	mV	2, 3
		+V <sub>CC</sub> = 4V, -V <sub>CC</sub> = -26V,		-5.0	5.0	mV	1
\/	Input Offeet Veltage	V <sub>CM</sub> = 11V		-7.0	7.0	mV	2, 3
$V_{IO}$	Input Offset Voltage			-5.0	5.0	mV	1
				-7.0	7.0	mV	2, 3
		.)/ .5)/		-5.0	5.0	mV	1
		$\pm V_{CC} = \pm 5V$		-7.0	7.0	mV	2, 3
		+V <sub>CC</sub> = 26V, -V <sub>CC</sub> = -4V,		-0.4	0.2	nA	1
		V <sub>CM</sub> = -11V		-10	50	nA	2
.1	Innut Bing Coment			-0.2	0.2	nA	1
±I <sub>IB</sub> Input Bias Current			-10	50	nA	2	
		$+V_{CC} = 4V, -V_{CC} = -26V,$		-0.2	1.2	nA	1
		V <sub>CM</sub> = 11V		-10	70	nA	2
	land Offert Coment			-0.1	0.1	nA	1
I <sub>IO</sub>	Input Offset Current			-20	20	nA	2
+PSRR	Power Supply Rejection Ratio	$+V_{CC} = 20V \text{ to } 10V, -V_{CC} = -15V$		80		dB	1, 2, 3
-PSRR	Power Supply Rejection Ratio	$+V_{CC} = 15V$ , $-V_{CC} = -20V$ to $-10V$		80		dB	1, 2, 3
CMRR	Input Voltage Common Mode Rejection	V <sub>CM</sub> = -11V to +11V		80		dB	1, 2, 3
+I <sub>OS</sub>	Output Short Circuit Current	t ≤ 25mS		-80		mA	1, 2, 3
-l <sub>os</sub>	Output Short Circuit Current	t ≤ 25mS			80	mA	1, 2, 3
	Cumply Current				7.0	mA	1, 2
I <sub>CC</sub>	Supply Current				8.0	mA	3
A)/ / AT	land Offert Veltane	25°C ≤ T <sub>A</sub> ≤ +125°C		-30	30	μV/°C	2
$\Delta V_{IO}$ / $\Delta T$	Input Offset Voltage	-55°C ≤ T <sub>A</sub> ≤ 25°C	See <sup>(1)</sup>	-30	30	μV/°C	3
/	Output Valta as Cuis a	$R_L = 10K\Omega$		12		V	4, 5, 6
+V <sub>OP</sub>	Output Voltage Swing	$R_L = 2K\Omega$		10		V	4, 5, 6
V	Output Valta as Cuis a	$R_L = 10K\Omega$			-12	V	4, 5, 6
-V <sub>OP</sub>	Output Voltage Swing	$R_L = 2K\Omega$			-10	V	4, 5, 6
۸	Open Lean Voltage Cair	B 2KO V 40V	See <sup>(2)</sup>	50		V/mV	4
-A <sub>VS</sub>	Open Loop Voltage Gain	$R_L = 2K\Omega$ , $V_O = -10V$	See /-/	25		V/mV	5, 6
. ^	Open Lean Voltage Cair	D 01/0 1/ 101/	Sec (2)	50		V/mV	4
+A <sub>VS</sub>	Open Loop Voltage Gain	$R_L = 2K\Omega, V_O = 10V$	See <sup>(2)</sup>	25		V/mV	5, 6
A <sub>VS</sub>	Open Loop Voltage Gain	$R_L = 10K\Omega, V_O = \pm 2V,$ $\pm V_{CC} = \pm 5V$	See <sup>(2)</sup>	20		V/mV	4, 5, 6

<sup>(1)</sup> Calculated parameter.

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<sup>2)</sup> Datalog reading in K = V/mV.

#### **Electrical Characteristics AC Parameters**

The following conditions apply, unless otherwise specified.  $\pm V_{CC} = \pm 15V$ ,  $V_{CM} = 0V$ 

Symbol	Parameter	Parameter Conditions No		Min	Max	Unit	Sub- group
TR <sub>TR</sub>	Transient Response Rise Time	$A_V = 1, V_I = 50 \text{mV},$ $C_L = 100 \text{pF}, R_L = 2 \text{K}\Omega$	See <sup>(1)</sup>		200	nS	7, 8A, 8B
TR <sub>OS</sub>	Transient Response Overshoot	$A_V = 1, V_I = 50 mV,$ $C_L = 100 pF, R_L = 2 K\Omega$	See <sup>(1)</sup>		40	%	7, 8A, 8B
00 01 0 1	Class Bata	V 5V45 .5V		7.0		V/µS	7
SR+	Slew Rate	$V_I = -5V$ to $+5V$		5.0		V/µS	8A, 8B
SR-	Class Data	V <sub>I</sub> = +5V to -5V		7.0		V/µS	7
SK-	Slew Rate			5.0		V/µS	8A, 8B
NI <sub>BB</sub>	Noise Broadband	BW = 10Hz to 15KHz, $R_S = 0\Omega$	See <sup>(2)</sup>		15	μV <sub>RMS</sub>	7
NI <sub>PC</sub>	Noise Popcorn	BW = 10Hz to 15KHz, $R_S = 100K\Omega$	See <sup>(2)</sup>		80	$\mu V_{PK}$	7
CS	Channel Separation	$R_L = 2K\Omega$ , $V_I = \pm 10V$	See <sup>(2)</sup>	80		dB	7
±tS	Settling Time	A <sub>V</sub> = 1	See <sup>(1)</sup>		1500	nS	12

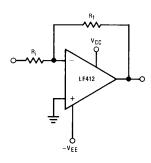
<sup>(1)</sup> Bench test.

#### **Electrical Characteristics DC Drift Parameters**

The following conditions apply, unless otherwise specified.  $\pm V_{CC} = \pm 15V$ ,  $V_{CM} = 0V$  Delta calculations are performed at group B5, only.

Symbol	Parameter	Conditions	Notes	Min	Max	Unit	Sub- group
V <sub>IO</sub>	Input Offset Voltage			-1.0	1.0	mV	1
$\pm I_{IB}$	Input Bias Current			-0.1	0.1	nA	1

#### **Typical Connection**



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<sup>(2)</sup> Test on either A360, AC or bench test.



#### **Typical Performance Characteristics**

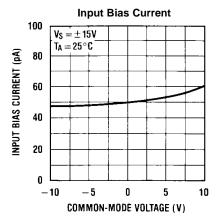


Figure 3.

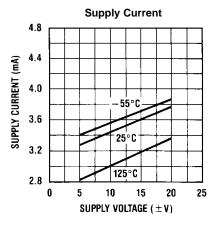
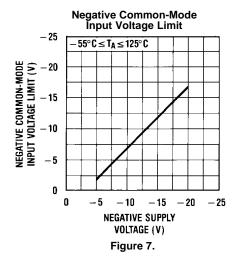
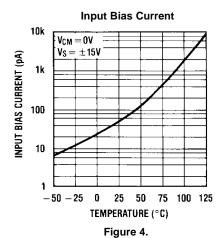


Figure 5.





Positive Common-Mode Input Voltage Limit 25  $-55^{\circ}C \le T_{A} \le 125^{\circ}C$ POSITIVE COMMON-MODE INPUT VOLTAGE LIMIT (V) 20 15 10 5 0 0 5 10 15 20 25 POSITIVE SUPPLY VOLTAGE (V) Figure 6.

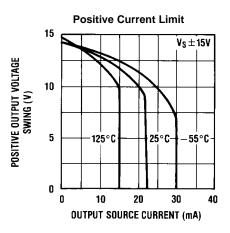


Figure 8.

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INSTRUMENTS

# Typical Performance Characteristics (continued) Negative Current Limit Output V

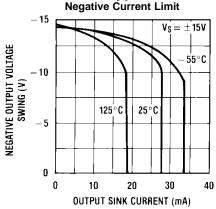


Figure 9.

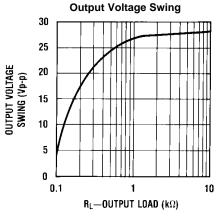


Figure 11.

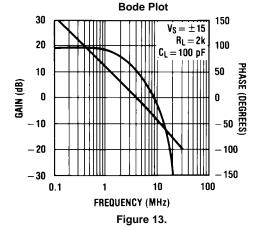
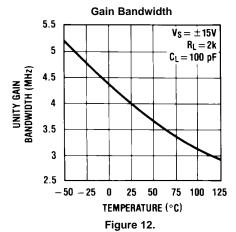
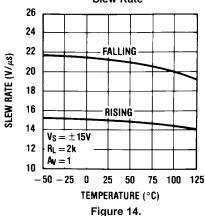


Figure 10.

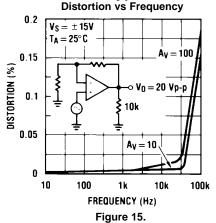


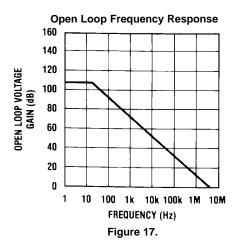
Slew Rate

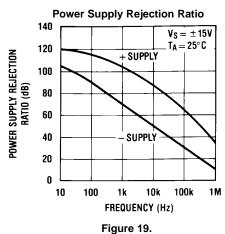


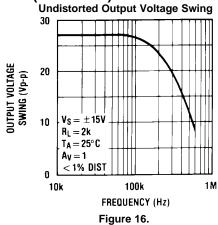
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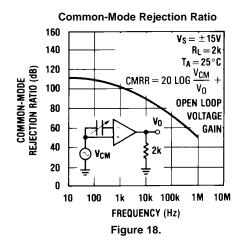
#### **Typical Performance Characteristics (continued)**

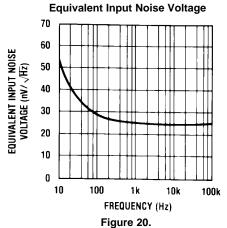






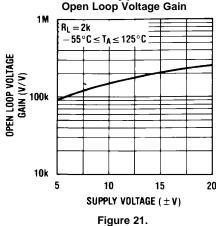


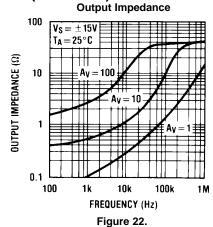


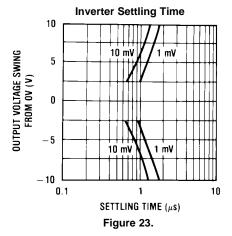


**INSTRUMENTS** 

# Typical Performance Characteristics (continued) Open Loop Voltage Gain Output



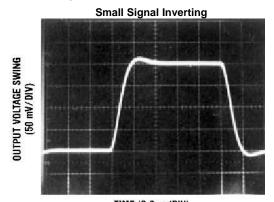




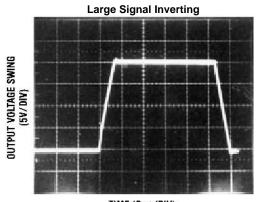
#### TEXAS INSTRUMENTS

#### **Pulse Response**

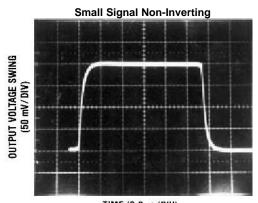
#### $R_L$ =2 $k\Omega$ , $C_L$ =10 pF



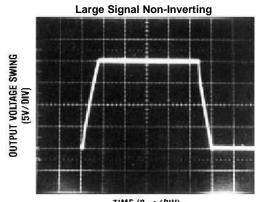
TIME (0.2  $\mu$ s/DIV) Figure 24.



TIME (2 μs/DIV) Figure 26.



TIME (0.2  $\mu$ s/DIV) Figure 25.



TIME (2 μs/DIV) Figure 27.

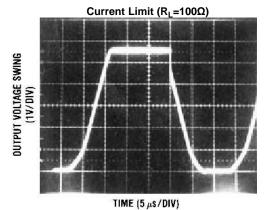


Figure 28.

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#### APPLICATION HINTS

The LF412 JFET input dual op amp is internally trimmed (BI-FET II™) providing very low input offset voltages and specified input offset voltage drift. These JFETs have large reverse breakdown voltages from gate to source and drain eliminating the need for clamps across the inputs. Therefore, large differential input voltages can easily be accommodated without a large increase in input current. The maximum differential input voltage is independent of the supply voltages. However, neither of the input voltages should be allowed to exceed the negative supply as this will cause large currents to flow which can result in a destroyed unit.

Exceeding the negative common-mode limit on either input will cause a reversal of the phase to the output and force the amplifier output to the corresponding high or low state.

Exceeding the negative common-mode limit on both inputs will force the amplifier output to a high state. In neither case does a latch occur since raising the input back within the common-mode range again puts the input stage and thus the amplifier in a normal operating mode.

Exceeding the positive common-mode limit on a single input will not change the phase of the output, however, if both inputs exceed the limit, the output of the amplifier may be forced to a high state.

The amplifiers will operate with a common-mode input voltage equal to the positive supply; however, the gain bandwidth and slew rate may be decreased in this condition. When the negative common-mode voltage swings to within 3V of the negative supply, an increase in input offset voltage may occur.

Each amplifier is individually biased by a zener reference which allows normal circuit operation on ±6.0V power supplies. Supply voltages less than these may result in lower gain bandwidth and slew rate.

The amplifiers will drive a 2 k $\Omega$  load resistance to  $\pm 10$ V over the full temperature range. If the amplifier is forced to drive heavier load currents, however, an increase in input offset voltage may occur on the negative voltage swing and finally reach an active current limit on both positive and negative swings.

Precautions should be taken to ensure that the power supply for the integrated circuit never becomes reversed in polarity or that the unit is not inadvertently installed backwards in a socket as an unlimited current surge through the resulting forward diode within the IC could cause fusing of the internal conductors and result in a destroyed unit.

As with most amplifiers, care should be taken with lead dress, component placement and supply decoupling in order to ensure stability. For example, resistors from the output to an input should be placed with the body close to the input to minimize "pick-up" and maximize the frequency of the feedback pole by minimizing the capacitance from the input to ground.

A feedback pole is created when the feedback around any amplifier is resistive. The parallel resistance and capacitance from the input of the device (usually the inverting input) to AC ground set the frequency of the pole. In many instances the frequency of this pole is much greater than the expected 3 dB frequency of the closed loop gain and consequently there is negligible effect on stability margin. However, if the feedback pole is less than approximately 6 times the expected 3 dB frequency a lead capacitor should be placed from the output to the input of the op amp. The value of the added capacitor should be such that the RC time constant of this capacitor and the resistance it parallels is greater than or equal to the original feedback pole time constant.

Product Folder Links: LF412JAN



# **Typical Application**

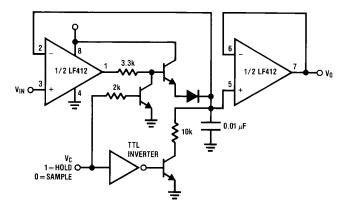


Figure 29. Single Supply Sample and Hold



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#### **REVISION HISTORY**

Date Released Revision		Section	Changes		
12/08/2010	Α	New Release to Corporate format	1 MDS datasheet converted into Corporate datasheet format. MJLF412-X Rev 0C1 will be archived.		
3/27/2013	Α	All Sections	Changed layout of National Data Sheet to TI format		

Product Folder Links: LF412JAN



#### PACKAGE OPTION ADDENDUM

30-Sep-2016

#### PACKAGING INFORMATION

Orderable Device Status F	Package Type	Package Drawing	Pins I	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
JL412BPA OBSOLETE	CDIP	NAB	8	4.9	TBD	Call TI	Call TI	-55 to 125	JL412BPA Q JM38510/ 11905BPA ACO 11905BPA >T	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD**: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

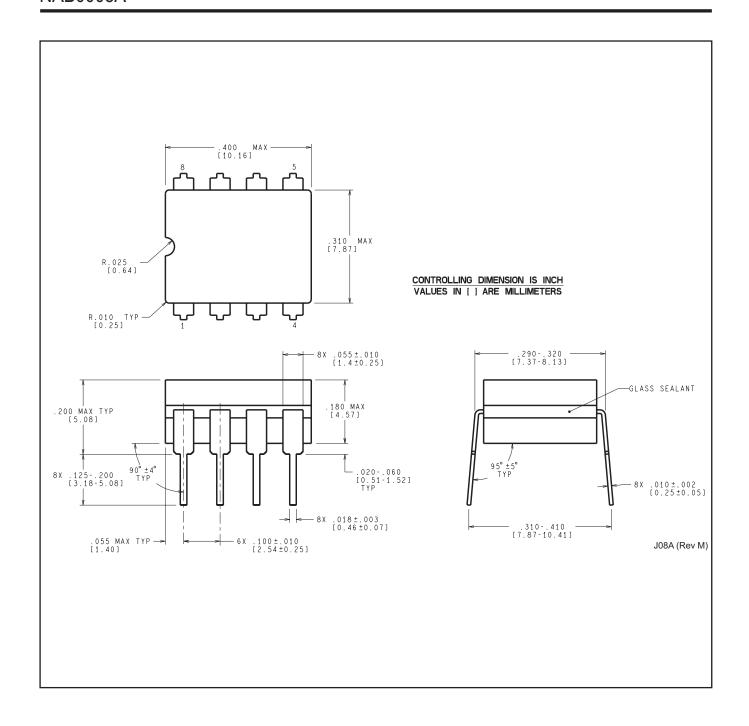
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# **PACKAGE OPTION ADDENDUM**

30-Sep-2016

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